

● **General Description**

The TF050N04M combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ . This device is ideal for load switch and battery protection applications.

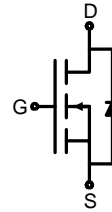
● **Features**

- Advance high cell density Trench technology
- Low  $R_{DS(ON)}$  to minimize conductive loss
- Low Gate Charge for fast switching
- Low Thermal resistance

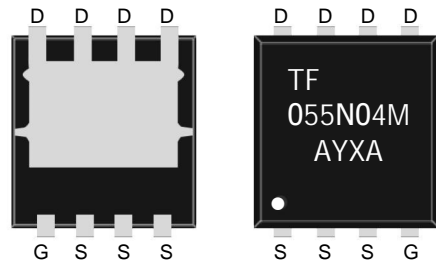
● **Application**

- MB/VGA Vcore
- SMPS 2<sup>nd</sup> Synchronous Rectifier
- POL application
- BLDC Motor driver

● **Product Summary**



$V_{DS} = 40V$     $I_D = 50A$   
 $R_{DS(ON)(10V \text{ typ})} = 4.9m\Omega$   
 $R_{DS(ON)(4.5V \text{ typ})} = 6.0m\Omega$



**PDFNWB3.3x3.3-8L**

● **Ordering Information:**

Part NO.	TF050N04M
Marking 1	TF050N04M
Marking 2	TF:tuofeng; AA:device code; Y:year code; X:Week
MOQ	5000

● **Absolute Maximum Ratings** ( $T_C = 25^\circ C$ )

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D @ T_C = 25^\circ C$	50	A
	$I_D @ T_C = 75^\circ C$	40	A
	$I_D @ T_C = 100^\circ C$	35	A
Pulsed Drain Current ①	$I_{DM}$	180	A
Total Power Dissipation	$P_D @ T_C = 25^\circ C$	60	W
Total Power Dissipation	$P_D @ T_A = 25^\circ C$	2.0	W
Operating Junction Temperature	$T_J$	-55 to 150	$^\circ C$
Storage Temperature	$T_{STG}$	-55 to 150	$^\circ C$

Note: ① Pulse Test : Pulse width  $\leq 300\mu s$ , Duty cycle  $\leq 2\%$  ;



Shenzhen Tuofeng Semiconductor Technology Co., Ltd  
**N-CHANNEL ENHANCEMENT MODE POWER MOSFET**

**TF050N04M**

Single Pulse Avalanche Energy	$E_{AS}$	180	mJ			
Avalanche Current	$I_{AS} I_{AR}$	30	A			
<b>•Thermal resistance</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Min.</b>	<b>Typ.</b>	<b>Max.</b>	<b>Unit</b>	
Thermal resistance, junction - case	$R_{thJC}$	-	-	3.2	° C/W	
Thermal resistance, junction - ambient	$R_{thJA}$	-	-	57	° C/W	
Soldering temperature, wave soldering for 8s	$T_{sold}$	-	-	265	° C	
<b>•Electronic Characteristics</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Condition</b>	<b>Min.</b>	<b>Typ</b>	<b>Max.</b>	<b>Unit</b>
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	40			V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_D = 250\mu A$	1.0	1.5	2.5	V
Drain-Source Leakage Current	$I_{DSS}$	$V_{DS} = 40V, V_{GS} = 0V$			1.0	$\mu A$
Gate- Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$			$\pm 100$	nA
Static Drain-source On Resistance	$R_{DS(ON)}$	$V_{GS} = 10V, I_D = 30A$		4.9	6.0	m $\Omega$
		$V_{GS} = 4.5V, I_D = 20A$		6.0	7.5	m $\Omega$
Forward Transconductance	$g_{FS}$	$V_{DS} = 25V, I_D = 10A$		18		S
Source-drain voltage	$V_{SD}$	$I_S = 20A$			1.20	V
<b>•Electronic Characteristics</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Condition</b>	<b>Min.</b>	<b>Typ</b>	<b>Max.</b>	<b>Unit</b>
Input capacitance	$C_{iss}$	$V_{ds} = 20V, V_{gs} = 0V$ $f = 1MHz$	-	2174	-	pF
Output capacitance	$C_{oss}$		-	146	-	
Reverse transfer capacitance	$C_{rss}$		-	150	-	
<b>•Gate Charge characteristics(<math>T_a = 25^\circ C</math>)</b>						
<b>Parameter</b>	<b>Symbol</b>	<b>Condition</b>	<b>Min.</b>	<b>Typ</b>	<b>Max.</b>	<b>Unit</b>
Gate Resistance	$R_g$	$f = 1MHz$		1.5		$\Omega$
Total gate charge	$Q_g$	$V_{DD} = 20V$ $I_D = 20A$ $V_{GS} = 10V$	-	43.2	-	nC
Gate - Source charge	$Q_{gs}$		-	23.9	-	
Gate - Drain charge	$Q_{gd}$		-	15.2	-	
Turn-ON Delay time	$t_{D(on)}$	$V_{GS} = 10V, V_{DS} = 20V$ $R_G = 3.0\Omega, I = 20A$		8.8		ns
Turn-ON Rise time	$t_r$			111		ns
Turn-Off Delay time	$t_{D(off)}$			36.6		ns
Turn-Off Fall time	$t_f$			103		ns

Fig.1 Power Dissipation

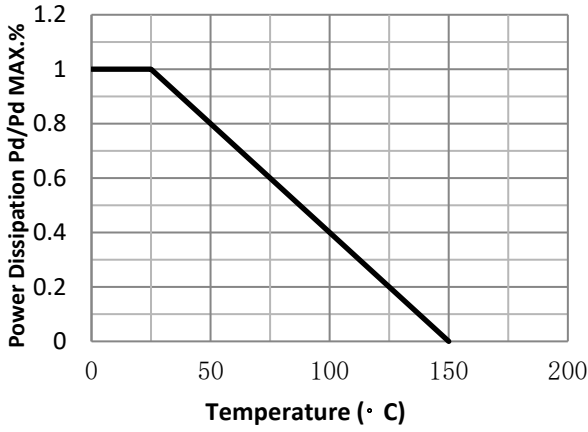


Fig.2 Typical output Characteristics

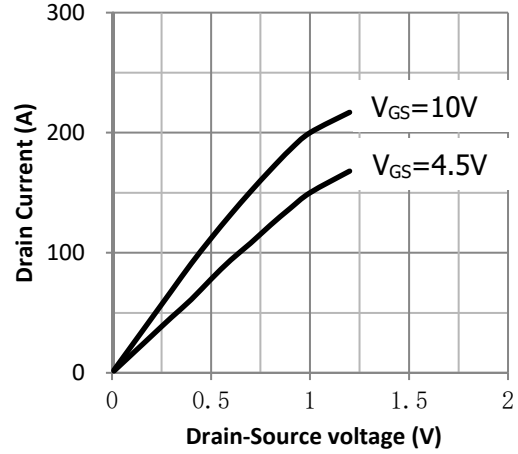


Fig.3 Threshold Voltage V.S Junction Temperature

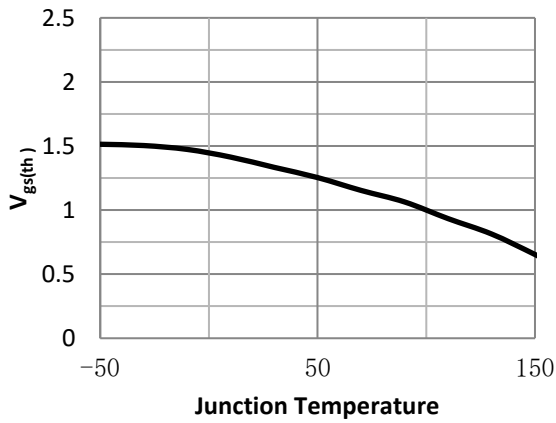


Fig.4 Resistance V.S Drain Current

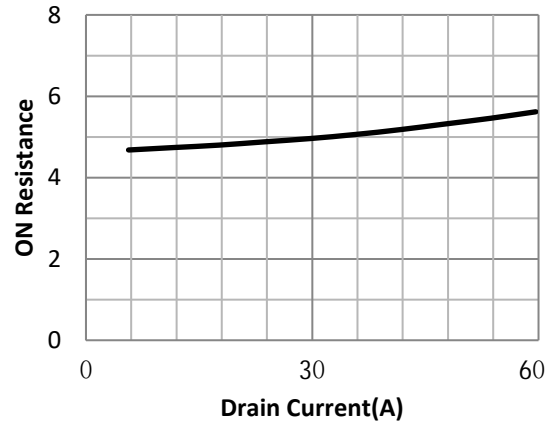


Fig.5 On-Resistance VS Gate Source Voltage

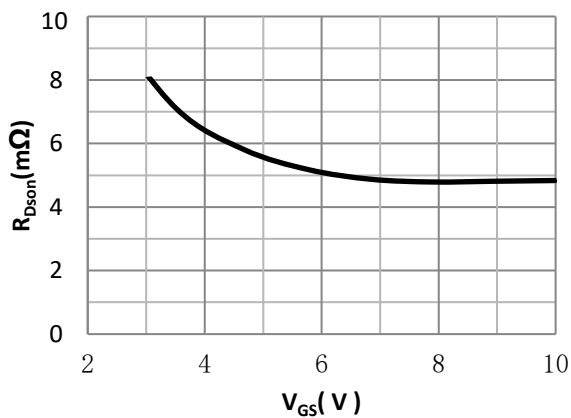


Fig.6 On-Resistance V.S Junction Temperature

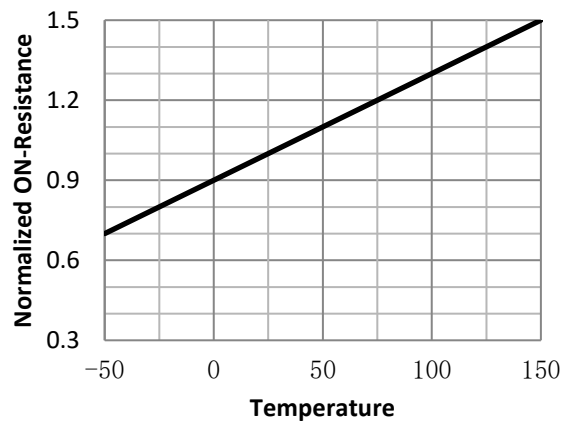


Fig.7 Switching Time Measurement Circuit

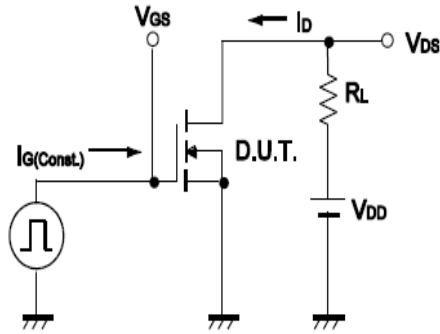


Fig.8 Gate Charge Waveform

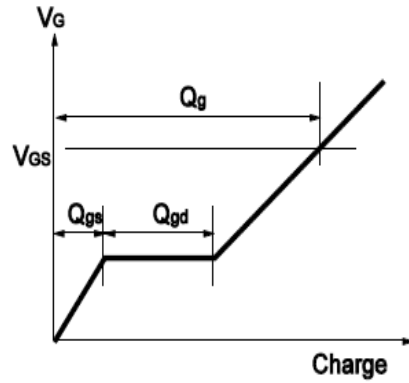


Fig.9 Switching Time Measurement Circuit

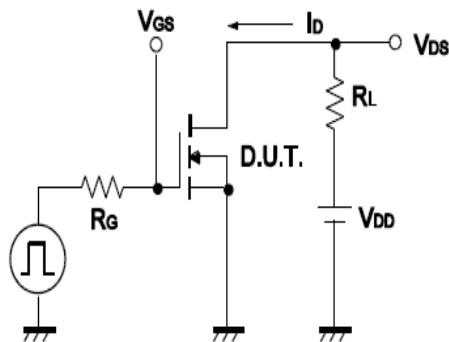


Fig.10 Gate Charge Waveform

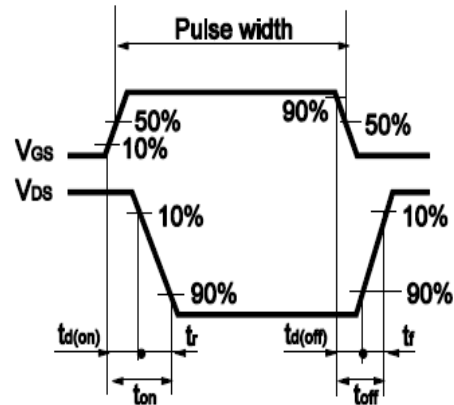


Fig.11 Avalanche Measurement Circuit

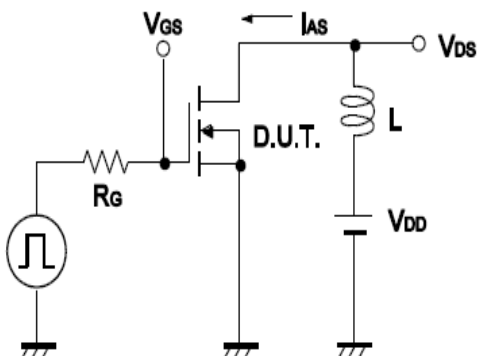
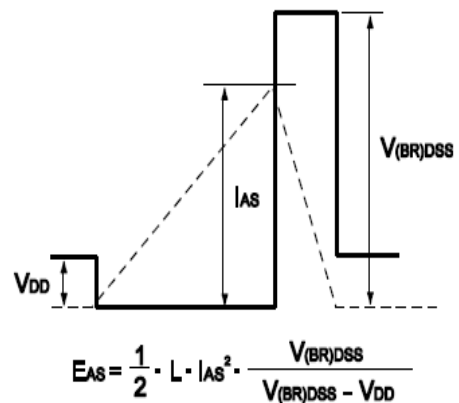
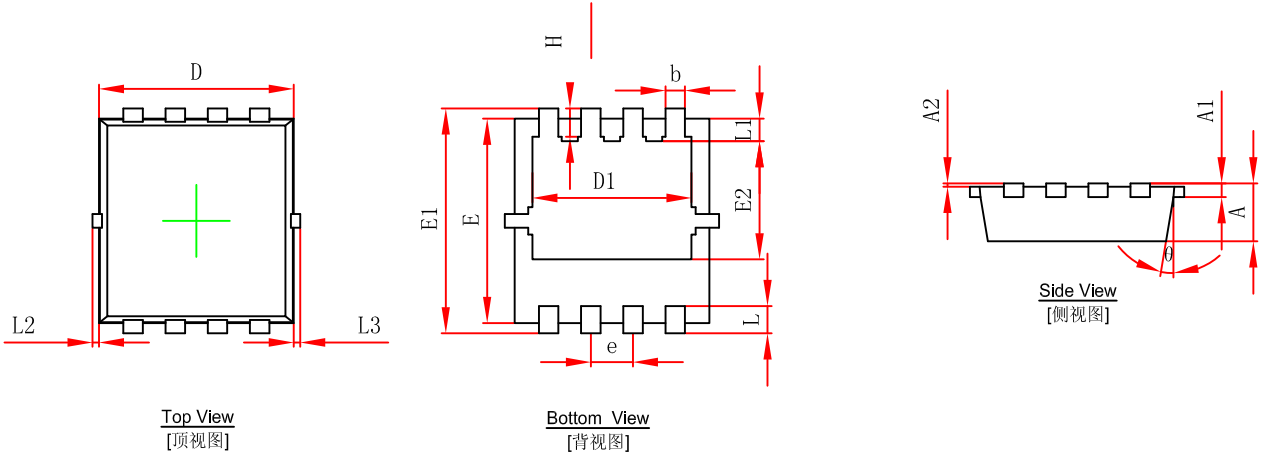


Fig.12 Avalanche Waveform

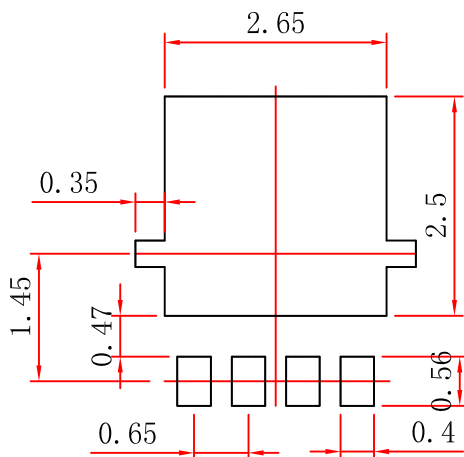


**PDFNWB3.3x3.3-8L Package Outline Dimensions**



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.650	0.850	0.026	0.033
A1	0.152 REF.		0.006 REF.	
A2	0~0.05		0~0.002	
D	2.900	3.100	0.114	0.122
D1	2.300	2.600	0.091	0.102
E	2.900	3.100	0.114	0.122
E1	3.150	3.450	0.124	0.136
E2	1.535	1.935	0.060	0.076
b	0.200	0.400	0.008	0.016
e	0.550	0.750	0.022	0.030
L	0.300	0.500	0.012	0.020
L1	0.180	0.480	0.007	0.019
L2	0~0.100		0~0.004	
L3	0~0.100		0~0.004	
H	0.315	0.515	0.012	0.020
θ	9°	13°	9°	13°

**PDFNWB3.3x3.3-8L Suggested Pad Layout**



**Note:**

1. Controlling dimension: in millimeters.
2. General tolerance: ±0.05mm.
3. The pad layout is for reference purposes only.